

**Search Notes****Application/Control No.**

10/652,787

**Examiner**

Chau Nguyen

**Applicant(s)/Patent under Reexamination**

LAYZELL ET AL.

**Art Unit**

2176

**SEARCHED**

Class	Subclass	Date	Examiner
715	517	2/23/2006	CN
715	518	2/23/2006	CN
715	519	2/23/2006	CN
715	503	2/23/2006	CN
715	508	2/23/2006	CN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Reports	02/23/2006	CN
	2/24/2006	CN
NPL Search on IEEE Database	3/1/2006	CN
Updated Search on East Reports	8/11/2006	CN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner